

## DK-104088-UL

IEC SYSTEM FOR MUTUAL RECOGNITION OF TEST CERTIFICATES FOR ELECTRICAL EQUIPMENT (IECEE) CB SCHEME

CB SCHEME	
CB TEST CERTIFICATE	
Product	Mother board

Name and address of the applicant INTEL CORPORATION

2200 Mission College Blvd Santa Clara, CA 95054 USA

Name and address of the manufacturer INTEL CORPORATION

2200 Mission College Blvd Santa Clara, CA 95054 USA

Name and address of the factory

MAINTEK COMPUTER (SUZHOU) CO LTD

233 JIN FENG RD NEW DISTRICT SUZHOU JIANGSU 215011

CHINA

Additional Information on page 2

Ratings and principal characteristics 19Vdc

Trademark / Brand (if any)

Note: When more than one factory, please report on page 2

INTEL



Type of Customer's Testing Facility (CTF) Stage used

Model / Type Ref.

NUC11TNB, xNUC11xTNBx (where x can be a combination of alphanumeric characters or blank)

Additional information (if necessary may also be reported on page 2)

Additionally evaluated to EN 60950-1: 2006 / A11: 2009 / A1: 2010 / A12: 2011 / A2: 2013

National Difference specified in the CB Test Report

Additional Information on page 2

A sample of the product was tested and found to be in conformity with

IEC 60950-1:2005/AMD1:2009, IEC 60950-1:2005/AMD2:2013, IEC 60950-1:2005

As shown in the Test Report Ref. No. which forms part of this Certificate

ASL20080622 issued on 2020-10-05

This CB Test Certificate is issued by the National Certification Body

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UL (JP), Marunouchi Trust Tower Main Building 6F, 1-8-3 Marunouchi, Chiyoda-ku, Tokyo 100-0005, JAPAN

For full legal entity names see www.ul.com/ncbnames

UL (CA), 7 Underwriters Road, Toronto, M1R 3B4 Ontario, CANADA

Date: 2020-10-13 Signature:

Jan-Erik Storgaard